# Abstracts

## Two-Dimensional Field Mapping in MMIC-Substrates by Electro-Optic Sampling Technique

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*W. Mertin, C. Bohm, L.J. Balk and E. Kubalek. "Two-Dimensional Field Mapping in MMIC-Substrates by Electro-Optic Sampling Technique." 1992 MTT-S International Microwave Symposium Digest 92.3 (1992 Vol. III [MWSYM]): 1443-1446.*

For the first time two-dimensional substrate internal field mapping of monolithic microwave integrated structures on GaAs by direct electro-optic sampling is presented. Measurements up to 8.5 GHz have been made. It will be shown that this test technique is very useful for internal function and failure analysis of MMIC.

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